## Search Notes

Application/Control No.	Applicant(s)/Patent Under Reexamination
10824434	YOON ET AL.
Examiner	Art Unit
Tan, Alvin H	2173

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SEARCHED			
Class	Subclass	Date	Examiner
715	744, 747	5/3/07 (Updated 6/21/09)	/AT/ (/AT/)

SEARCH NOTES			
Search Notes	Date	Examiner	
715/744-747 (text search only - see search history printout)	5/3/07 (Updated 6/21/09)	/AT/ (/AT/)	
EAST (US-PGPUB, USPAT, USOCR, EPO, JPO, IBM_TDB) - See Search	5/3/07 (Updated	/AT/ (/AT/)	
History Printout	6/21/09)		
NPL - ACM Portal	5/4/07	AT	

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